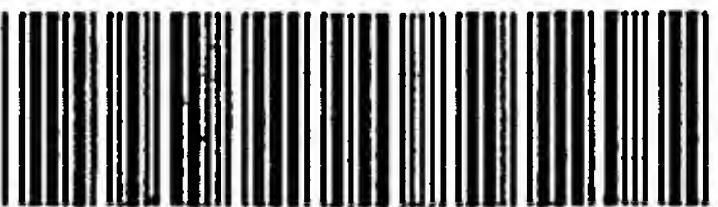


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## **Search Notes**



**Application/Control No.**

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Examiner

EDMUND H. LEE

**Applicant(s)/Patent under  
Reexamination**

MASER ET AL.

Art Unit

1791

**SEARCHED**

# **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**